



Integrated Device Technology, Inc.  
2975 Stender Way, Santa Clara, CA - 95054

## PRODUCT/PROCESS CHANGE NOTICE (PCN)

PCN #: **F0301-01**                      DATE: 4/9/2003  
 Product Affected:  
 IDT72V3611, IDT72V3612, IDT72V3613, IDT72V3614  
  
 Date Effective: 7/9/2003

MEANS OF DISTINGUISHING CHANGED DEVICES:  
 Product Mark  
 Back Mark  
 Date Code  
 Other

Contact: Dasharath Patel  
 Title: Quality Assurance Manager                      Attachment::  Yes                       No  
 Phone #: (408) 330-1488  
 Fax #: (408) 330-1450                      Samples: Available now  
 E-mail: [Dasharath.Patel@idt.com](mailto:Dasharath.Patel@idt.com)

**DESCRIPTION AND PURPOSE OF CHANGE:**

<input type="checkbox"/> Die Technology <input type="checkbox"/> Wafer Fabrication Process <input type="checkbox"/> Assembly Process <input type="checkbox"/> Equipment <input type="checkbox"/> Material <input type="checkbox"/> Testing <input checked="" type="checkbox"/> Manufacturing Site <input type="checkbox"/> Data Sheet <input type="checkbox"/> Other	<p>As a part of IDT's consolidation of wafer fab manufacturing operations, the devices listed above are transferred from FAB 2 (Salinas, CA) to FAB 4 (Hillsboro, OR). There will be no change in manufacturing technology. Starting 07/09/2003, customers will receive material manufactured either at FAB 2 or FAB 4. Please see below for means of distinguishing inventory.</p> <table border="0"> <tr> <td>Fab2 material mark</td> <td>Z-Step</td> <td>Date Code:</td> <td>Zyyww</td> </tr> <tr> <td>Fab4 material mark</td> <td>Y-Step</td> <td>Date Code:</td> <td>Yyyww</td> </tr> <tr> <td></td> <td></td> <td>yy: Year</td> <td>ww: Work Week</td> </tr> </table>	Fab2 material mark	Z-Step	Date Code:	Zyyww	Fab4 material mark	Y-Step	Date Code:	Yyyww			yy: Year	ww: Work Week
Fab2 material mark	Z-Step	Date Code:	Zyyww										
Fab4 material mark	Y-Step	Date Code:	Yyyww										
		yy: Year	ww: Work Week										

**RELIABILITY/QUALIFICATION SUMMARY:**

Please see attachment for qualification summary

**CUSTOMER ACKNOWLEDGMENT OF RECEIPT:**

IDT records indicate that you require written notification of this change. Please use the acknowledgement below or E-Mail to grant approval or request additional information. If IDT does not receive acknowledgement within 30 days of this notice it will be assumed that this change is acceptable.  
 IDT reserves the right to ship either version manufactured after the process change effective date until the inventory on the earlier version has been depleted.

Customer: \_\_\_\_\_  **Approval for shipments prior to effective date.**  
 Name/Date: \_\_\_\_\_ E-Mail Address: \_\_\_\_\_  
 Title: \_\_\_\_\_ Phone# /Fax# : \_\_\_\_\_

**CUSTOMER COMMENTS:** \_\_\_\_\_

**IDT ACKNOWLEDGMENT OF RECEIPT:**

RECD. BY: \_\_\_\_\_ DATE: \_\_\_\_\_



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## PRODUCT/PROCESS CHANGE NOTICE (PCN)

### ATTACHMENT - PCN #: F0301-01

**PCN Type:** Wafer Fabrication Site Change

**Data Sheet Change:** None

**Detail of Change:** Transfer of manufacturing site from FAB 2 (Salinas, CA) to FAB 4 (Hillsboro, OR)  
for the following devices:  
IDT72V3611, IDT72V3612, IDT72V3613 and IDT72V3614

### Conversion schedule (Estimated)

Samples	Available upon request
Production Shipments	7/9/2003



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### ATTACHMENT - PCN #: F0301-01

**Qualification Plan:** QFI-02-16

**Test Vehicle:** IDT72V3614

Test Description/Condition	Test Methods	SS /# Fails	Test Results
Temperature Cycling (-65°C to +150°C, 500 cyc)	MIL-STD-883, Method 1010	45/0	45 / 0
Life Test (+125°C, 1000 hrs)	MIL-STD-883, Method 1005	116/0	116 / 0
Latch-Up Immunity (+ - I and V stress, + - 100 mA Trigger)	EIA/JESD 78	10/0	10 / 0
ESD Human Body Model	MIL-STD-883, Method 3015	9/0	9 / 0
ESD Charge Device Model	JESD22-C101	6/0	6 / 0

#### Characterization Data:

Characterization data is available upon request.